

# Lecture 04: Statistics

## Introduction to Machine Learning [25737]

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- 3 Empirical Risk Minimization (ERM)
- 4 Maximum a Posteriori (MAP) or Regularization
- 5 Bayesian Model Averaging
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Except explicitly cited, the reference for the material in slides is:

- Murphy, K. P. (2022). *Probabilistic machine learning: an introduction*. MIT press.

# Section 1

## Basic Problem

## Model Fitting (Training)

Machine learning generally deals with finding parameterized mapping  $f(\cdot; \theta)$  (Task) based on dataset  $\mathcal{D}$  (Experience). This is known as model fitting (training). Training is generally formulated as:

$$\hat{\theta} = \underset{\theta}{\operatorname{argmin}} \mathcal{L}(\theta)$$

where  $\mathcal{L}(\theta)$  is known as loss function.

## Model Parameters

There are two important points considering model parameters:

- Point estimate  $\hat{\theta}$
- Uncertainty or confidence in the estimate (*Inference*)

## Section 2

# Maximum Likelihood Estimation (MLE)

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## Maximum Likelihood Estimation (MLE)

The MLE for supervised learning is defined as:

$$\hat{\theta}_{\text{mle}} \triangleq \underset{\theta}{\operatorname{argmax}} \overbrace{p(\{\mathbf{x}_n, \mathbf{y}_n\}_{n=1}^N | \theta)}^{\mathcal{D}}$$

adding the independency of training example we have:

$$p(\mathcal{D} | \theta) = \prod_{n=1}^N p(\mathbf{x}_n, \mathbf{y}_n | \theta)$$

The above distribution can be reformulated as:

$$p(\mathcal{D} | \theta) = \prod_{n=1}^N p(\mathbf{y}_n | \mathbf{x}_n, \theta) \overbrace{p(\mathbf{x}_n | \theta)}^{p(\mathbf{x}_n)}$$

Thus we can find MLE using the following problem:

$$\hat{\theta}_{\text{mle}} \triangleq \underset{\theta}{\operatorname{argmax}} \prod_{n=1}^N p(\mathbf{y}_n | \mathbf{x}_n, \theta)$$

# Negative Log Likelihood (NLL)

## Negative Log Likelihood (NLL)

From Slide 7 we have:

$$\hat{\theta}_{\text{mle}} \triangleq \underset{\theta}{\operatorname{argmax}} \prod_{n=1}^N p(\mathbf{y}_n | \mathbf{x}_n, \theta)$$

Log likelihood (LL) is defined as:

$$LL(\theta) \triangleq \log \prod_{n=1}^N p(\mathbf{y}_n | \mathbf{x}, \theta) = \sum_{n=1}^N \log p(\mathbf{y}_n | \mathbf{x}_n, \theta)$$

Adding a negative sign we reach the Negative Log Likelihood (NLL) as:

$$NLL(\theta) \triangleq -\log \prod_{n=1}^N p(\mathbf{y}_n | \mathbf{x}, \theta) = -\sum_{n=1}^N \log p(\mathbf{y}_n | \mathbf{x}_n, \theta)$$

And optimization problem to find  $\hat{\theta}_{\text{mle}}$  becomes minimization as:

$$\hat{\theta}_{\text{mle}} = \underset{\theta}{\operatorname{argmin}} NLL(\theta)$$



## Equivalent to MAP estimation

Under uniform prior distribution ( $p(\boldsymbol{\theta}) \propto 1$ ),  $\hat{\boldsymbol{\theta}}_{mle} = \hat{\boldsymbol{\theta}}_{map}$

## Equivalence of MAP and MLE Under Uniform Prior

The maximum a Posteriori estimation for model parameters is:

$$\hat{\boldsymbol{\theta}}_{map} = \underset{\boldsymbol{\theta}}{\operatorname{argmax}} p(\boldsymbol{\theta}|\mathcal{D}) = \underset{\boldsymbol{\theta}}{\operatorname{argmax}} \frac{p(\mathcal{D}|\boldsymbol{\theta})p(\boldsymbol{\theta})}{p(\mathcal{D})}$$

where  $p(\mathcal{D})$  is independent of  $\boldsymbol{\theta}$  and we assume uniform prior ( $p(\boldsymbol{\theta}) \propto 1$ ). Thus:

$$\hat{\boldsymbol{\theta}}_{map} = \underset{\boldsymbol{\theta}}{\operatorname{argmax}} p(\mathcal{D}|\boldsymbol{\theta}) = \hat{\boldsymbol{\theta}}_{mle}$$

# Kullback Leibler (KL) divergence

## Kullback Leibler (KL) divergence

KL divergence is a common function for comparing two distributions  $p$  and  $q$  defined over a random variable  $Y$ . It is formulated as:

- Discrete RV:  $D_{\text{KL}}(p||q) \triangleq \sum_{y \in \mathcal{Y}} p(y) \log \frac{p(y)}{q(y)} = \mathbb{E}_p[\log \frac{p(y)}{q(y)}]$
- Continuous RV:  $D_{\text{KL}}(p||q) \triangleq \int_{y \in \mathcal{Y}} p(y) \log \frac{p(y)}{q(y)} dy = \mathbb{E}_p[\log \frac{p(y)}{q(y)}]$

## Kullback Leibler (KL) divergence

- KL divergence is not a distance measure because:
  - It is not symmetric:  $D_{\text{KL}}(p||q) \neq D_{\text{KL}}(q||p)$
  - It need not satisfy triangular inequality.
- $D_{\text{KL}}(p||q) \geq 0$
- $D_{\text{KL}}(p||q) = 0$  iff  $p = q$

## Empirical Data Distribution

In a supervised problem over dataset  $\mathcal{D} = \{(\mathbf{x}_n, \mathbf{y}_n)\}_{n=1}^N$ , the empirical distribution is defined as:

$$p_D(\mathbf{x}) = \frac{1}{N} \sum_{n=1}^N \delta(\mathbf{x} - \mathbf{x}_n)$$

$$p_D(\mathbf{y}|\mathbf{x}) = \begin{cases} \delta(\mathbf{y} - \mathbf{y}_n) & \text{if } \mathbf{x} = \mathbf{x}_n, n = 1, \dots, N \\ \text{ND} & \text{O.W.} \end{cases}$$

$$p_D(\mathbf{x}, \mathbf{y}) = p_D(\mathbf{y}|\mathbf{x})p_D(\mathbf{x}) = \frac{1}{N} \sum_{n=1}^N \delta(\mathbf{x} - \mathbf{x}_n)\delta(\mathbf{y} - \mathbf{y}_n)$$

## Minimizing the Distance Between Model and Data Distributions

Assume the conditional empirical distribution  $p_D(\mathbf{y}|\mathbf{x})$  and model distribution  $p(\mathbf{y}|\mathbf{x}, \boldsymbol{\theta})$ . The expected KL divergence between these distributions over empirical distribution  $p_D(\mathbf{x})$  is:

$$\begin{aligned}\mathbb{E}_{p_D(\mathbf{x})}[D_{\text{KL}}(p_D(\mathbf{y}|\mathbf{x})||p(\mathbf{y}|\mathbf{x}, \boldsymbol{\theta})))] &= \int_{\mathbf{x}} p_D(\mathbf{x}) \left[ \int_{\mathbf{y}} p_D(\mathbf{y}|\mathbf{x}) \log \frac{p_D(\mathbf{y}|\mathbf{x})}{p(\mathbf{y}|\mathbf{x}, \boldsymbol{\theta})} d\mathbf{y} \right] d\mathbf{x} \\ &= \overbrace{\int_{\mathbf{x}} \int_{\mathbf{y}} p_D(\mathbf{x}, \mathbf{y}) \log p_D(\mathbf{y}|\mathbf{x})}^{\text{constant}} - \int_{\mathbf{x}} \int_{\mathbf{y}} \frac{1}{N} \sum_{n=1}^N \delta(\mathbf{x} - \mathbf{x}_n) \delta(\mathbf{y} - \mathbf{y}_n) \log p(\mathbf{y}|\mathbf{x}, \boldsymbol{\theta}) \\ &= \text{constant} - \frac{1}{N} \sum_{n=1}^N \log p(\mathbf{y}_n|\mathbf{x}_n, \boldsymbol{\theta}) = \text{constant} + NLL(\boldsymbol{\theta})\end{aligned}$$

Thus we have:

$$\hat{\boldsymbol{\theta}}_{mle} = \underset{\boldsymbol{\theta}}{\operatorname{argmin}} \mathbb{E}_{p_D(\mathbf{x})}[D_{\text{KL}}(p_D(\mathbf{y}|\mathbf{x})||p(\mathbf{y}|\mathbf{x}, \boldsymbol{\theta}))]$$

## MLE for Bernolli Distribution

Suppose:

- $Y \sim \text{Ber}(\theta)$  representing coin toss ( $Y = 1$  represents head)
- $\theta = p(Y = 1)$
- $\mathcal{D} = \{y_1, \dots, y_N\}$

Compute  $\hat{\theta}_{mle}$ .

# MLE Example

## MLE for Bernolli Distribution

Suppose:

- $Y \sim \text{Ber}(\theta)$  representing coin toss ( $Y = 1$  represents head)
- $\theta = p(Y = 1)$
- $\mathcal{D} = \{y_1, \dots, y_N\}$

Compute  $\hat{\theta}_{mle}$ .

## Solution

$$\begin{aligned} NNL(\theta) &= -\log \prod_{n=1}^N p(y_n | \theta) = -\log \prod_{n=1}^N \theta^{\mathbb{I}(y_n=1)} (1-\theta)^{\mathbb{I}(y_n=0)} \\ &= -\sum_{n=1}^N \mathbb{I}(y_n = 1) \log \theta + \mathbb{I}(y_n = 0) \log(1 - \theta) = -[N_1 \log \theta + N_0 \log(1 - \theta)] \end{aligned}$$

where  $N_1 = \sum_{n=1}^N \mathbb{I}(y_n = 1)$  (number of heads) and  $N_0 = \sum_{n=1}^N \mathbb{I}(y_n = 0)$  (number of tails).  $N_1$  and  $N_2$  are called the *Sufficient Statistics* of the data, since they summarize everything we need to know about  $\mathcal{D}$ .  $N = N_1 + N_2$  is called the *Sample Size*.  $\hat{\theta}_{mle}$  can be found as:

$$\frac{d}{d\theta} NLL(\theta) = 0 \Rightarrow \hat{\theta}_{mle} = \frac{N_1}{N_1 + N_0} \quad (\text{Empirical fraction of heads})$$

## MLE for Gaussian Distribution

Suppose:

- $Y \sim \mathcal{N}(\mu, \sigma^2)$
- $\theta = (\mu, \sigma^2)$
- $\mathcal{D} = \{y_1, \dots, y_N\}$

Compute  $\hat{\theta}_{mle} = \{\hat{\mu}_{mle}, \hat{\sigma}_{mle}^2\}$ .

# MLE Example

## MLE for Gaussian Distribution

Suppose:

- $Y \sim \mathcal{N}(\mu, \sigma^2)$
- $\theta = (\mu, \sigma^2)$
- $\mathcal{D} = \{y_1, \dots, y_N\}$

Compute  $\hat{\theta}_{mle} = \{\hat{\mu}_{mle}, \hat{\sigma}_{mle}^2\}$ .

## Solution

$$NLL(\mu, \sigma^2) = \frac{1}{2\sigma^2} \sum_{n=1}^N (y_n - \mu)^2 + \frac{N}{2} \log(2\pi\sigma^2)$$

$\bar{y} = \frac{1}{N} \sum_{n=1}^N y_n$  and  $s^2 = \frac{1}{N} \sum_{n=1}^N y_n^2$  are called the *Sufficient Statistics* of the data, since they summarize everything we need to know about  $\mathcal{D}$  to calculate  $\hat{\mu}_{mle}$  and  $\hat{\sigma}_{mle}^2$  as:

$$\begin{cases} \frac{d}{d\mu} NLL(\mu, \sigma^2) = 0 \\ \frac{d}{d\sigma^2} NLL(\mu, \sigma^2) = 0 \end{cases} \Rightarrow \begin{cases} \hat{\mu}_{mle} = \frac{1}{N} \sum_{n=1}^N y_n = \bar{y} \\ \hat{\sigma}_{mle}^2 = \frac{1}{N} \sum_{n=1}^N (y_n - \hat{\mu})^2 = s^2 - \bar{y}^2 \end{cases}$$



## MLE for MVN

Suppose:

- $\mathbf{y} \sim \mathcal{N}(\boldsymbol{\mu}, \boldsymbol{\Sigma})$
- $\boldsymbol{\theta} = (\boldsymbol{\mu}, \boldsymbol{\Sigma})$
- $\mathcal{D} = \{\mathbf{y}_1, \dots, \mathbf{y}_N\}$

Compute  $\hat{\boldsymbol{\theta}}_{mle} = \{\hat{\boldsymbol{\mu}}_{mle}, \hat{\boldsymbol{\Sigma}}_{mle}\}$ .

## MLE for MVN

Suppose:

- $\mathbf{y} \sim \mathcal{N}(\boldsymbol{\mu}, \boldsymbol{\Sigma})$
- $\boldsymbol{\theta} = (\boldsymbol{\mu}, \boldsymbol{\Sigma})$
- $\mathcal{D} = \{\mathbf{y}_1, \dots, \mathbf{y}_N\}$

Compute  $\hat{\boldsymbol{\theta}}_{mle} = \{\hat{\boldsymbol{\mu}}_{mle}, \hat{\boldsymbol{\Sigma}}_{mle}\}$ .

## Solution

$$LL(\boldsymbol{\mu}, \boldsymbol{\Sigma}) = \frac{N}{2} \log |\boldsymbol{\Lambda}| - \frac{1}{2} \sum_{n=1}^N (\mathbf{y}_n - \boldsymbol{\mu})^T \boldsymbol{\Lambda} (\mathbf{y}_n - \boldsymbol{\mu})$$

$\bar{\mathbf{y}} = \frac{1}{N} \sum_{n=1}^N \mathbf{y}_n$  and  $\mathbf{S} = \frac{1}{N} \sum_{n=1}^N \mathbf{y}_n \mathbf{y}_n^T$  are called the *Sufficient Statistics* of the data, since they summarize everything we need to know about  $\mathcal{D}$  to calculate  $\hat{\boldsymbol{\mu}}_{mle}$  and  $\hat{\boldsymbol{\Sigma}}_{mle}$  as:

$$\begin{cases} \frac{\partial}{\partial \boldsymbol{\mu}} NLL(\boldsymbol{\mu}, \boldsymbol{\Sigma}) = 0 \\ \frac{\partial}{\partial \boldsymbol{\Sigma}} NLL(\boldsymbol{\mu}, \boldsymbol{\Sigma}) = 0 \end{cases} \Rightarrow \begin{cases} \hat{\boldsymbol{\mu}}_{mle} = \frac{1}{N} \sum_{n=1}^N \mathbf{y}_n = \bar{\mathbf{y}} \\ \hat{\boldsymbol{\Sigma}}_{mle} = \frac{1}{N} \sum_{n=1}^N (\mathbf{y}_n - \bar{\mathbf{y}})(\mathbf{y}_n - \bar{\mathbf{y}})^T = \mathbf{S} - \bar{\mathbf{y}}\bar{\mathbf{y}}^T \end{cases}$$

## Section 3

# Empirical Risk Minimization (ERM)

## ERM

Remember MLE where we have the following problem:

$$\hat{\theta}_{mle} = \underset{\theta}{\operatorname{argmin}} \sum_{n=1}^N \overbrace{-\log p(\mathbf{y}_n | \mathbf{x}_n, \theta)}^{l(\mathbf{y}_n; \mathbf{x}_n, \theta)}$$

We can generalize this result by replacing conditional log loss with any other loss, to get:

$$\mathcal{L}(\theta) = \frac{1}{N} \sum_{n=1}^N l(\mathbf{y}_n; \mathbf{x}_n, \theta)$$

The above is known as Empirical Risk Minimization (ERM). It is loss expectation with respect to empirical distribution.

## Sample Loss Functions

Assume:

- A probabilistic binary classifier as:  $p(y|\mathbf{x}, \boldsymbol{\theta}) = \sigma(y\eta) = \frac{1}{1+e^{-y\eta}}$  where  $\eta = f(\mathbf{x}; \boldsymbol{\theta})$  is logg odds and  $y \in \{-1, +1\}$ .

We can define different loss functions as:

Name	$l(y; \mathbf{x}_n, \boldsymbol{\theta})$
Misclassification	$\mathbb{I}(y\eta < 0)$
NLL	$-\log_2 p(y \mathbf{x}, \boldsymbol{\theta}) = \log_2(1 + e^{-y\eta})$
Hing loss	$\max(0, 1 - y\eta) = (1 - y\eta)_+$
Exp loss	$e^{y\eta}$

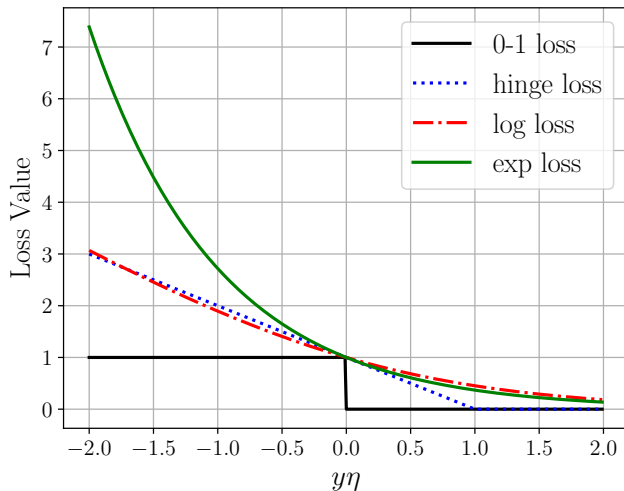


Figure: Loss functions for binary classification

## Section 4

# Maximum a Posteriori (MAP) or Regularization

# Problem with MLE

## Overfitting in MLE

Suppose the example of coin tossing with  $N = 3$  where we observe 3 heads. Thus we have:

$$\hat{\theta}_{mle} = \frac{N_1}{N_1 + N_0} = 1$$

In this case, overfitting has occurred.

## Regularization

Regularization is the process of designing and adding a penalty term to NLL (or empirical risk) so as to control overfitting. Thus we have:

$$\mathcal{L}(\boldsymbol{\theta}; \lambda) = \left[ \frac{1}{N} \sum_{n=1}^N l(\mathbf{y}_n; \mathbf{x}_n, \boldsymbol{\theta}) \right] + \lambda C(\boldsymbol{\theta})$$

where:

- $\lambda \geq 0$  is the regularization parameter
- $C(\boldsymbol{\theta})$  is some form of complexity penalty



## From Regularization to MAP

Assume  $C(\boldsymbol{\theta}) = -\log p(\boldsymbol{\theta})$  and  $\lambda = 1$ . Then:

$$\begin{aligned}\mathcal{L}(\boldsymbol{\theta}; 1) &= - \left[ \sum_{n=1}^N \log p(\mathbf{y}_n | \mathbf{x}_n, \boldsymbol{\theta}) + \log p(\boldsymbol{\theta}) \right] \\ &= -\log p(\boldsymbol{\theta} | \{\mathbf{x}_n, \mathbf{y}_n\}_{n=1}^N) + \text{const}\end{aligned}$$

Thus minimizing the  $\mathcal{L}(\boldsymbol{\theta}; 1)$  is equivalent to maximizing the posterior and we have:

$$\hat{\boldsymbol{\theta}}_{map} = \underset{\boldsymbol{\theta}}{\operatorname{argmin}} \mathcal{L}(\boldsymbol{\theta}; 1)$$

## MAP for Bernolli Distribution

Suppose:

- $Y \sim Ber(\theta)$  representing coin toss ( $Y = 1$  represents head)
- $\theta = p(Y = 1)$
- $\mathcal{D} = \{y_1, \dots, y_N\}$
- $p(\theta) = \text{Beta}(\theta|a, b) = \frac{\theta^{a-1}(1-\theta)^{b-1}}{B(a,b)}$  (Prior Distribution)

Compute  $\hat{\theta}_{map}$ .

# MAP Example

## MAP for Bernolli Distribution

Suppose:

- $Y \sim Ber(\theta)$  representing coin toss ( $Y = 1$  represents head)
- $\theta = p(Y = 1)$
- $\mathcal{D} = \{y_1, \dots, y_N\}$
- $p(\theta) = \text{Beta}(\theta|a, b) = \frac{\theta^{a-1}(1-\theta)^{b-1}}{B(a,b)}$  (Prior Distribution)

Compute  $\hat{\theta}_{map}$ .

## Solution

$$\begin{aligned}\hat{\theta}_{map} &= \underset{\theta}{\operatorname{argmin}} - \log \prod_{n=1}^3 p(y_n|\theta) - \log p(\theta) \\ &= (N_1 + a - 1) \log(\theta) + (N_0 + b - a) \log(1 - \theta) = \frac{N_1 + a - 1}{N_1 + N_0 + a + b - 2}\end{aligned}$$

## MAP for Bernolli Distribution (Continue)

$$\hat{\theta}_{map} = \frac{N_1 + a - 1}{N_1 + N_0 + a + b - 2}$$

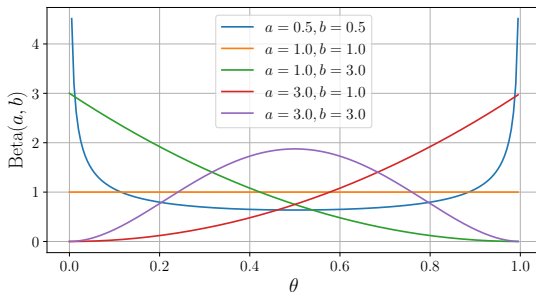


Figure: Probability density function for Beta distribution

## Challenge in Selecting $\lambda$

As we see before the regularized loss is defined as:

$$\mathcal{L}(\boldsymbol{\theta}; \lambda) = \left[ \frac{1}{N} \sum_{n=1}^N l(\mathbf{y}_n; \mathbf{x}_n, \boldsymbol{\theta}) \right] + \lambda C(\boldsymbol{\theta})$$

But how to Select  $\lambda$ :

- Large value of  $\lambda \Rightarrow$  Staying near prior (*Underfitting*)
- Small value of  $\lambda \Rightarrow$  Focus on minimizing empirical risk (*Overfitting*)

# Selecting Regularization Parameter

## Using Validation Set

Define  $R_\lambda(\boldsymbol{\theta}, \mathcal{D}) = \frac{1}{|\mathcal{D}|} \sum_{(\mathbf{x}, \mathbf{y}) \in \mathcal{D}} l(\mathbf{y}; \mathbf{x}, \boldsymbol{\theta}) + \lambda C(\boldsymbol{\theta})$ . Then we select  $\lambda$  as:

- Partition data into two disjoint set  $\mathcal{D}_{\text{train}}$  (training set) and  $\mathcal{D}_{\text{valid}}$  (validation or development set). Usually we put 80% for training and 20% for validation
- For each value of  $\lambda$  compute:  $\hat{\boldsymbol{\theta}}_\lambda(\mathcal{D}_{\text{train}}) = \operatorname{argmin}_{\boldsymbol{\theta}} R_\lambda(\boldsymbol{\theta}, \mathcal{D}_{\text{train}})$
- Compute the validation risk:  $R_\lambda^{\text{val}} = R_0(\hat{\boldsymbol{\theta}}_\lambda(\mathcal{D}_{\text{train}}), \mathcal{D}_{\text{valid}})$
- Select:  $\lambda^* = \operatorname{argmin}_\lambda R_\lambda^{\text{val}}$

Fit the model to entire dataset:  $\hat{\boldsymbol{\theta}}^* = \operatorname{argmin}_{\boldsymbol{\theta}} R_{\lambda^*}(\boldsymbol{\theta}, \mathcal{D})$

## Small Size Dataset

If the size of dataset is small, leaving aside 20% for a validation set can result in an unreliable estimate of the model parameters.

## Using Cross-Validation

Define  $R_\lambda(\boldsymbol{\theta}, \mathcal{D}) = \frac{1}{|\mathcal{D}|} \sum_{(\mathbf{x}, \mathbf{y}) \in \mathcal{D}} l(\mathbf{y}; \mathbf{x}, \boldsymbol{\theta}) + \lambda C(\boldsymbol{\theta})$ . Then we select  $\lambda$  as:

- Split data into  $K$  folds.
- For each fold  $k \in \{1, \dots, K\}$ , we train the model on all the folds but the  $k$ -th, and test on the  $k$ -th. So we calculate:

$$\text{Cross-validated risk: } R_\lambda^{\text{CV}} \triangleq \sum_{k=1}^K R_0(\hat{\boldsymbol{\theta}}_\lambda(\mathcal{D}_{-k}), \mathcal{D}_k)$$

- Select:  $\lambda^* = R_\lambda^{\text{CV}}$

Fit the model to entire dataset:  $\hat{\boldsymbol{\theta}}^* = \operatorname{argmin}_{\boldsymbol{\theta}} R_{\lambda^*}(\boldsymbol{\theta}, \mathcal{D})$

# Avoid Overfitting

## Early Stopping

Model parameters ( $\theta$ ) are learned in iterative optimization algorithm. In this method, the optimization is stopped as signs of overfitting are observed.

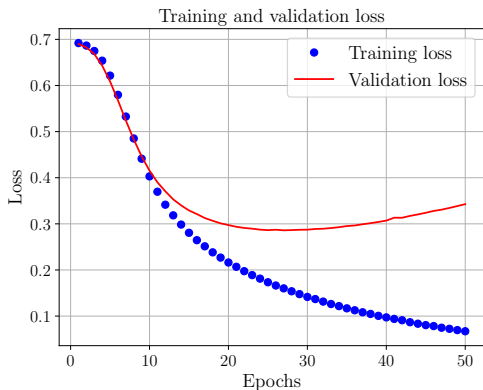


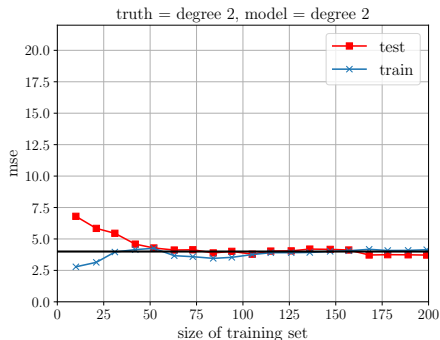
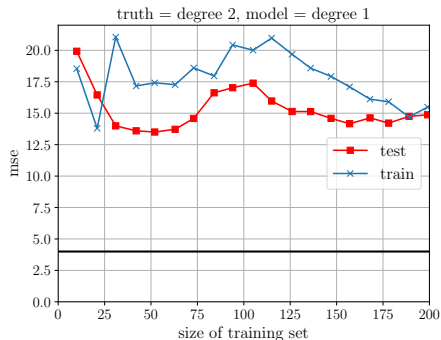
Figure: Tracking overfitting through iterations



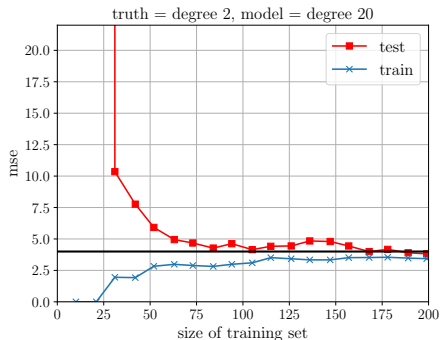
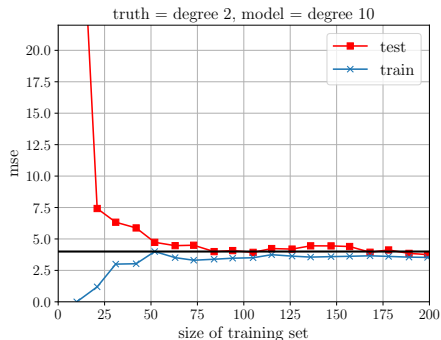
## Using More Data

As the amount of data increases, the chance of overfitting (for a model of fixed complexity) decreases (assuming the data contains suitably informative examples, and is not too redundant).

# Avoid Overfitting



# Avoid Overfitting



## Marginal Likelihood

Using Bayes rule, we can compute the posterior over parameters  $p(\boldsymbol{\theta}|\mathcal{D})$  as:

$$p(\boldsymbol{\theta}|\mathcal{D}) = \frac{p(\boldsymbol{\theta})p(\mathcal{D}|\boldsymbol{\theta})}{p(\mathcal{D})} = \frac{p(\boldsymbol{\theta})p(\mathcal{D}|\boldsymbol{\theta})}{\int p(\boldsymbol{\theta}')p(\mathcal{D}|\boldsymbol{\theta}')d\boldsymbol{\theta}'}$$

$p(\mathcal{D})$  in the denominator is called *marginal likelihood* since it is computed by marginalizing over the unknown parameters  $\boldsymbol{\theta}$ . This can be interpreted as:

$$p(\mathcal{D}) = \mathbb{E}_{p(\boldsymbol{\theta})}[p(\mathcal{D}|\boldsymbol{\theta})]$$

## Bayes Model Averaging (BMA)

In Bayes Model Averaging, we compute the *Posterior Predictive Distribution* over outputs given inputs by marginalizing out  $\boldsymbol{\theta}$  parameters as:

$$p(\mathbf{y}|\mathbf{x}, \mathcal{D}) = \int p(\mathbf{y}|\mathbf{x}, \boldsymbol{\theta})p(\boldsymbol{\theta}|\mathcal{D})d\boldsymbol{\theta}$$

## Section 5

# Bayesian Model Averaging

## Challenge

The possibility to compute posterior probability is one of the main challenges for BMA. The solution is to use conjugate prior to likelihood function.

## Bernoulli Likelihood - Beta Prior

Assume dataset samples are independent and identically distributed and comes from Bernoulli distribution where  $\theta = P(Y = 1)$ . Then:

- The likelihood is:  $p(\mathcal{D}|\theta) = \prod_{n=1}^N \theta^{N_1} (1 - \theta)^{N_0}$ 
  - $N_1 = \sum_{n=1}^N \mathbb{I}(y_n = 1)$  and  $N_0 = \sum_{n=1}^N \mathbb{I}(y_n = 0)$
- Beta is conjugate prior to Bernoulli likelihood thus:  
 $p(\theta) \propto \theta^{\check{\alpha}-1} (1 - \theta)^{\check{\beta}-1} = \text{Beta}(\theta|\check{\alpha}, \check{\beta})$

The posterior can be calculated as:

$$p(\theta|\mathcal{D}) = \text{Beta}(\theta|\hat{\alpha}, \hat{\beta}), \begin{cases} \hat{\alpha} \triangleq \check{\alpha} + N_1 \\ \hat{\beta} \triangleq \check{\beta} + N_0 \end{cases}$$

## Bernoulli Likelihood - Beta Prior (Continue)

- The parameters of the prior are called *hyper-parameters*
- Hyper-parameters play a role analogous to the sufficient statistics ( $N_1$  and  $N_2$ ); they are therefore often called *pseudo counts*.
- The strength of the prior is controlled by  $\check{N} = \check{\alpha} + \check{\beta}$ ; this is called the *equivalent sample size* (analogous to  $N = N_0 + N_1$ ).

# Bayesian Model Averaging

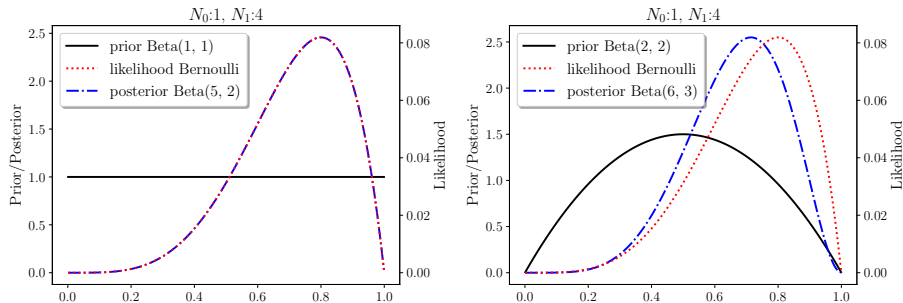


Figure: Uniform and non-Uniform prior distribution for small dataset size



# Bayesian Model Averaging

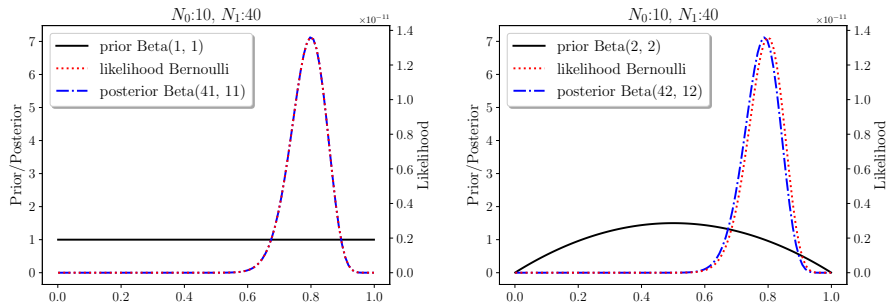


Figure: Uniform and non-Uniform prior distribution for large dataset size

## Bernoulli Likelihood - Beta Prior (Continue)

We can use different point estimates (*Plug-in approximation*) as:

$$\hat{\theta}_{\text{map}} = \frac{\check{\alpha} + N_1 - 1}{\check{\alpha} + N_1 - 1 + \check{\beta} + N_0 - 1}$$

$$\hat{\theta}_{\text{mle}} = \frac{N_1}{N_1 + N_0}$$

$$\bar{\theta} \triangleq \mathbb{E}[\theta|\mathcal{D}] = \frac{\hat{\alpha}}{\hat{\alpha} + \hat{\beta}} = \lambda \overbrace{\frac{\check{\alpha}}{\check{N}}}^{\bar{\theta}_p} + (1 - \lambda) \overbrace{\frac{\hat{\theta}_{\text{mle}}}{N_1}}^{\bar{\theta}_{\text{mle}}}, \lambda = \frac{\check{N}}{N + \check{N}}$$

The posterior variance can show the uncertainty in our estimate and can be calculated as:

$$\mathbb{V}[\theta|\mathcal{D}] = \frac{\hat{\alpha}\hat{\beta}}{(\hat{\alpha} + \hat{\beta})^2(\hat{\alpha} + \hat{\beta} + 1)}$$

If  $N \gg \check{\alpha} + \check{\beta}$ , then the posterior variance can be simplified to:

$$\mathbb{V}[\theta|\mathcal{D}] \approx \frac{\hat{\theta}_{\text{mle}}(1 - \hat{\theta}_{\text{mle}})}{N}$$

## Bernoulli Likelihood - Beta Prior (Continue)

Using posterior predictive distribution we have:

$$\begin{aligned} p(y = 1|\mathcal{D}) &= \int_0^1 p(y = 1|\theta)p(\theta|\mathcal{D})d\theta \\ &= \int_0^1 \theta \text{Beta}(\theta|\hat{\alpha}, \hat{\beta})d\theta = \mathbb{E}[\theta|\mathcal{D}] = \frac{\hat{\alpha}}{\hat{\alpha} + \hat{\beta}} \end{aligned}$$

Now compare these two cases:

- Plug-in approximation with  $p(\theta) = \text{Beta}(\theta|2, 2)$  then
$$p(y = 1|\hat{\theta}_{\text{map}}) = \frac{N_1+1}{N_1+N_2+2}$$
- Posterior predictive distribution with  $p(\theta) = \text{Beta}(\theta|1, 1)$  then
$$p(y = 1) = \frac{N_1+1}{N_1+N_2+2}$$

## Section 6

# Approximate Posterior Inference

## Grid Approximation

Basis: Discretizing parameter space

- Partitioning the parameters space into finite set of possibilities, denoted  $\theta_1, \dots, \theta_K$
- Approximate the posterior using brute-force enumeration:

$$p(\theta = \theta_k | \mathcal{D}) = \frac{p(\mathcal{D} | \theta_k) p(\theta_k)}{p(\mathcal{D})} \approx \frac{p(\mathcal{D} | \theta_k) p(\theta_k)}{\sum_{k'=1}^K p(\mathcal{D} | \theta_{k'}) p(\theta_{k'})}$$

Notes:

- Not scalable with respect to parameter vector dimension (Exponential grow)

## Quadratic (Laplace) Approximation

Basis: Approximating posterior using MVN

- Rewrite the posterior as:

$$p(\boldsymbol{\theta}|\mathcal{D}) = \frac{1}{Z} e^{-\epsilon(\boldsymbol{\theta})}, \quad \begin{cases} \epsilon(\boldsymbol{\theta}) = -\log p(\boldsymbol{\theta}, \mathcal{D}) \\ Z = p(\mathcal{D}) \end{cases}$$

- Approximate  $\epsilon(\boldsymbol{\theta})$  around its mode ( $\hat{\boldsymbol{\theta}}_{\text{map}}$ ) using Taylor expansion:

$$\epsilon(\boldsymbol{\theta}) \approx \epsilon(\hat{\boldsymbol{\theta}}_{\text{map}}) + (\boldsymbol{\theta} - \hat{\boldsymbol{\theta}}_{\text{map}})^T \mathbf{g} + \frac{1}{2} (\boldsymbol{\theta} - \hat{\boldsymbol{\theta}}_{\text{map}})^T \mathbf{H} (\boldsymbol{\theta} - \hat{\boldsymbol{\theta}}_{\text{map}})$$

- $\mathbf{g}(\hat{\boldsymbol{\theta}}_{\text{map}}) = \mathbf{0}$  and we can compute  $\mathbf{H}$ , thus:  $\hat{p}(\boldsymbol{\theta}|\mathcal{D}) = \mathcal{N}(\boldsymbol{\theta}|\hat{\boldsymbol{\theta}}_{\text{map}}, \mathbf{H}^{-1})$

Notes:

- $\mathbf{H}$  is assumed to be diagonal
- Not suitable for skewed posterior
- Not suitable for constrained parameters

## Variational Approximation

Basis:

- Assuming approximate posterior distribution comes from family  $\mathcal{Q}$ , denoted  $q$
- Find  $q^*$  as:  $q^* = \operatorname{argmin}_{q \in \mathcal{Q}} D(q(\boldsymbol{\theta}), p(\boldsymbol{\theta}|\mathcal{D}))$  where:
  - $D$  is a discrepancy measure such as KL divergence

Notes:

- The approximation can be biased if due to the limitation  $q \in \mathcal{Q}$

## Markov Chain Monte Carlo (MCMC)

Basis: Generating samples from posterior

- Generate samples  $\boldsymbol{\theta}^s \sim p(\boldsymbol{\theta}|\mathcal{D})$  efficiently without having to evaluate normalization constant  $p(\mathcal{D})$
- Evaluate posterior by:

$$q(\boldsymbol{\theta}) \approx \frac{1}{S} \sum_{s=1}^S \delta(\boldsymbol{\theta} - \boldsymbol{\theta}^s)$$

Notes:

- Low convergence speed